

CLEAR LOGIC

CL3256A

Laser Processed Logic Device Family

Key Features

- ◆ Laser Processed Logic Device (LPLD™) technology offers the ultimate combination of performance, flexibility, and low cost
- ◆ Functionally, architecturally, and electrically compatible with industry-standard Altera® MAX® 3000
- ◆ High Density
 - 5,000 Usable gates
 - 256 Macrocells
 - 158 Maximum user I/O pins
- ◆ Laser fuse technology provides very fast, dense interconnect routing
- ◆ Low current consumption
- ◆ Supports 3.3 volt operation
- ◆ Alpha particle immune

CL3000 Product Family Overview

Feature	CL3128A	CL3256A
Useable Gates	2,500	5,000
Macrocells	128	256
Logic array Blocks	8	16
Max user I/O pins	96	158
Speed Grades	-4, -5, -7, -10	-5, -6, -7, -10
Packages	100-Pin TQFP 144-Pin TQFP	144-Pin TQFP 208-Pin PQFP

3KA tbl 01A

Description

The Clear Logic CL3000 Laser Processed Logic Device (LPLD[®]) family offers the ultimate combination of performance, flexibility, and cost. This family is a system level second source to Altera MAX[®] 3000A products. For designs not requiring in-system reprogrammability, design verification can be performed using the programmable Altera devices, and Clear Logic LPLDs can be used for low cost, high volume production.

Clear Logic's innovative laser-based technology eliminates NRE costs, test vector development, ordering minimums and long lead times. No re-simulation or re-layout is required, as the device uses a cell-based, PLD-like architecture. Clear Logic's NoFault[®] technology ensures complete test coverage through the use of specialized testing modes which are transparent to the user.

The Clear Logic CL3000 Laser Processed Logic Device family is based upon a large array of macrocells. Each macrocell contains a logic array with five product terms, a product-term select matrix, and a configurable register. A group of sixteen macrocells forms a block. Laser-configured metal fuses implement logical functions and control signal routing.

Laser configuration provides reduced cost and enhanced performance. These inherent performance benefits include extremely consistent propagation delays, reduced power consumption, and improved immunity to noise and upset events.

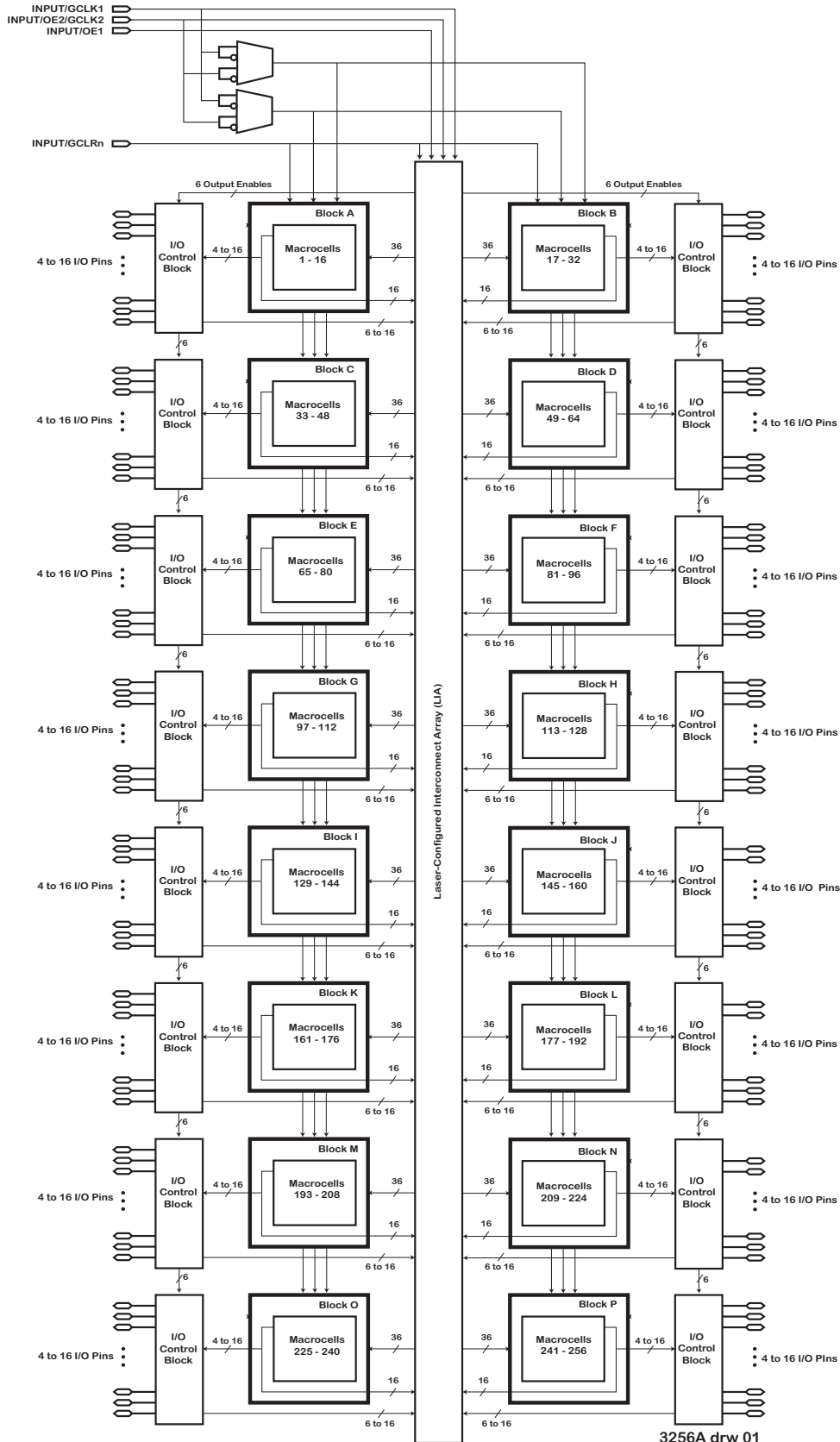
Additional Information

For further information on designing with the CL3000 LPLD family (See CL7000), please consult the following documents:

- ◆ AN-01: Requesting a First Article. This document provides instructions on how to submit a bitstream file for generation of first articles.
- ◆ AN-02: Clear Logic Packaging Guide. This document provides specifications and drawings for packages used by the CL7000 family.
- ◆ AN-09: CL7000 Technology White Paper. This document outlines the technologies employed by the CL7000 LPLD family.
- ◆ AN-10: Calculating CL7000 Power Consumption. This document provides guidelines for calculating power consumption based on design characteristics.
- ◆ AN-11: CL7000 Test Methodology. This document describes how Clear Logic provides 100% stuck-at fault coverage.

- ◆ AN-12: CL7000 LPLD Timing and Function Compatability. This document shows how a seamless conversion from CPLD to ASIC can be achieve with no additional engineering with Clear Logic.

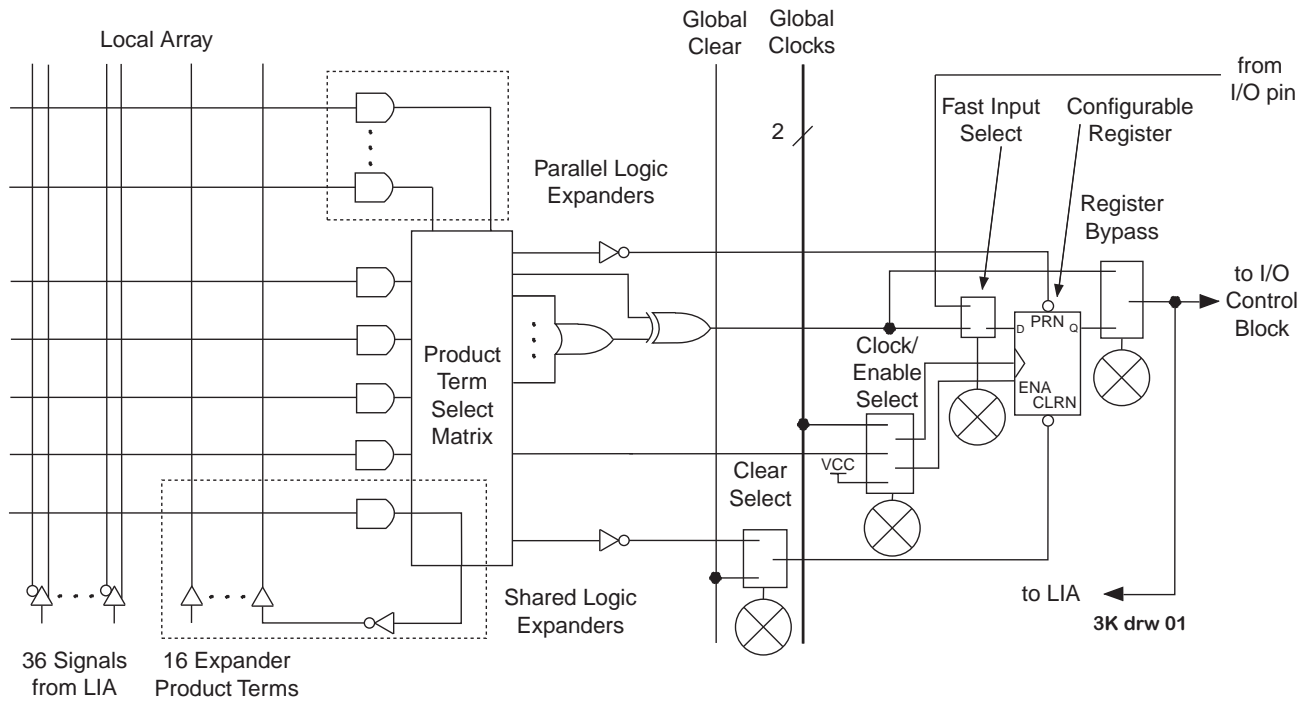
Block Diagram



3256A drw 01



Macrocell Diagram



Pin Configuration

Pin Name	144 pin TQFP	208 pin PQFP
INPUT/GCLK1	125	184
INPUT/GCLRn	127	182
INPUT/OE1	126	183
INPUT/OE2/GCLK2	128	181
TDI	4	176
TMS	20	127
TCK	89	30
TDO	104	189
GNDINT	52, 57, 124, 129	75, 82, 180, 185
GND	3, 13, 17, 26, 33, 59, 64, 77, 85, 94, 105, 114, 135	6, 14, 32, 40, 50, 72, 84, 94, 108, 116, 134, 142, 152, 174, 190, 200
VCCINT	51, 58, 123, 130	74, 83, 179, 186
VCCIO	24, 50, 73, 76, 95, 115, 144	5, 23, 41, 63, 85, 107, 125, 143, 165, 191
NC (No Connect)	-	1, 2, 51, 52, 53, 54, 103, 104, 105, 106, 155, 156, 157, 158, 207, 208
Total user I/O pins	116	158

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DC Electrical Specifications

Recommended Operating Conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CCINT}	Supply voltage, internal logic and input buffers		3.0	3.6	V
V _{CCIO}	Supply voltage for output drivers	3.3 volt operation	3.0	3.6	V
		2.5 volt operation	2.3	2.7	V
V _I	Input voltage		-0.5	5.75	V
V _O	Output voltage		0	V _{CCIO}	V
T _A	Ambient Operating temperature	Commercial temperature range	0	70	°C
		Industrial temperature range	-40	85	°C
T _J	Ambient Operating temperature	Commercial temperature range	0	90	°C
		Industrial temperature range	-40	105	°C
t _R	Input signal rise time			40	ns
t _F	Input signal fall time			40	ns

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Absolute Maximum Ratings

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	Supply voltage	With respect to ground	-0.5	4.6	V
V _I	DC input voltage ^[1]	With respect to ground	-2.0	5.75	V
I _{OUT}	DC output current, per pin		-25	25	mA
T _{STG}	Storage temperature	No bias	-65	150	°C
T _A	Ambient temperature	Under bias	-65	135	°C
T _J	Junction temperature	PQFP, and TFPF packages, Under bias		135	°C

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DC Electrical Specifications cont.

DC Electrical Characteristics (over the operating range)

Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	High-level input Voltage		1.7	5.75	V
V_{IL}	Input LOW Voltage ^[1]		-0.5	0.8	V
V_{OH}	3.3-V high-level TTL output Voltage	$I_{OH} = -8 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$	2.4		V
	3.3-V high-level CMOS output Voltage	$I_{OH} = -0.1 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$	$V_{CCIO}-0.2$		V
	2.5-V high-level output Voltage	$I_{OH} = -100 \mu\text{A DC}, V_{CCIO} = 2.30 \text{ V}$	2.1		V
		$I_{OH} = -1 \text{ mA DC}, V_{CCIO} = 2.30 \text{ V}$	2.0		
		$I_{OH} = -2 \text{ mA DC}, V_{CCIO} = 2.30 \text{ V}$	1.7		
V_{OL}	3.3-V high-level TTL output Voltage	$I_{OH} = 8 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$		0.45	V
	3.3-V high-level CMOS output Voltage	$I_{OH} = 0.1 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$		0.2	V
	2.5-V high-level output Voltage	$I_{OH} = 100 \mu\text{A DC}, V_{CCIO} = 2.30 \text{ V}$		0.2	V
		$I_{OH} = 1 \text{ mA DC}, V_{CCIO} = 2.30 \text{ V}$		0.4	V
		$I_{OH} = 2 \text{ mA DC}, V_{CCIO} = 2.30 \text{ V}$		0.7	V
I_{IN}	Input Leakage Current	$V_I = V_{CC}$ or GND	-10	10	μA
I_{OZ}	Output Leakage Current	$V_O = V_{CC}$ or GND	-10	10	μA

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Capacitance

Symbol	Parameter	Conditions	Min	Max	Unit
C_{IN}	Input Capacitance	$V_{IN} = 0 \text{ V}, f = 1.0 \text{ MHz}$		8	pF
C_{OUT}	Output Capacitance	$V_{OUT} = 0 \text{ V}, f = 1.0 \text{ MHz}$		8	pF

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AC Electrical Specifications

I/O Element Timing Parameters

Symbol	Parameter	Conditions	Speed: -4		Speed: -5		Speed: -6		Unit
			Min	Max	Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C _L = 35 pF		4.5		5.0		6.0	ns
t _{PD2}	I/O input to non-registered output	C _L = 35 pF		4.5		5.0		6.0	ns
t _{SU}	Global clock setup time		3.0		3.2		3.7		ns
t _H	Global clock hold time		0.0		0.0		0.0		ns
t _{CO1}	Global clock to output delay	C _L = 35 pF	1.0	2.8	1.0	3.0	1.0	3.3	ns
t _{CH}	Global clock high time		2.0		2.0		3.0		ns
t _{CL}	Global clock low time		2.0		2.0		3.0		ns
t _{ASU}	Array clock setup time		1.4		1.0		0.8		ns
t _{AH}	Array clock hold time		0.8		0.8		1.9		ns
t _{ACO1}	Array clock to output delay	C _L = 35 pF		4.4		5.2	1.0	6.2	ns
t _{ACH}	Array clock high time		2.0		2.0		3.0		ns
t _{ACL}	Array clock low time		2.0		2.0		3.0		ns
t _{CNT}	Minimum global clock period			5.2		5.5		6.4	ns
f _{CNT}	Max. internal global clock frequency		192.3		181.8		156.3		MHz
t _{ACNT}	Minimum array clock period			5.2		5.5		6.4	ns
f _{ACNT}	Max. internal array clock frequency		192.3		181.8		156.3		MHz

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AC Electrical Specifications cont.

External Timing Parameters

Speed: -7

Speed: -10

Symbol	Parameter	Conditions	Speed: -7		Speed: -10		Unit
			Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	$C_L = 35 \text{ pF}$		7.5		10.0	ns
t_{PD2}	I/O input to non-registered output	$C_L = 35 \text{ pF}$		7.5		10.0	ns
t_{SU}	Global clock setup time		4.9		6.6		ns
t_H	Global clock hold time		0.0		0.0		ns
t_{CO1}	Global clock to output delay	$C_L = 35 \text{ pF}$	1.0	4.5	1.0	5.9	ns
t_{CH}	Global clock high time		3.0		4.0		ns
t_{CL}	Global clock low time		3.0		4.0		ns
t_{ASU}	Array clock setup time		1.6		2.1		ns
t_{AH}	Array clock hold time		2.1		3.4		ns
t_{ACO1}	Array clock to output delay	$C_L = 35 \text{ pF}$		7.8		10.4	ns
t_{ACH}	Array clock high time		3.0		4.0		ns
t_{ACL}	Array clock low time		3.0		4.0		ns
t_{CNT}	Minimum global clock period			8.4		11.2	ns
f_{CNT}	Max. internal global clock frequency		119.0		89.3		MHz
t_{ACNT}	Minimum array clock period			8.4		11.2	ns
f_{ACNT}	Max. internal array clock frequency		119.0		89.3		MHz

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AC Electrical Specifications cont.

Internal Timing Parameters^[4]

Speed: -4 Speed: -5 Speed: -6

Symbol	Parameter	Conditions	Min	Max	Min	Max	Min	Max	Unit
t _{IN}	Input pad and buffer delay			0.3		0.3		0.3	ns
t _{IO}	I/O input pad and buffer delay			0.3		0.3		0.3	ns
t _{SEXP}	Shared expander delay			1.9		2.4		2.8	ns
t _{PEXP}	Parallel expander delay			0.5		0.6		0.5	ns
t _{LAD}	Logic array delay			1.9		2.5		2.5	ns
t _{LAC}	Logic control array delay			1.8		2.3		2.5	ns
t _{IOE}	Internal output enable delay			0.0		0.0		0.2	ns
t _{OD1}	Output buffer and pad delay Slow slew rate = off, V _{CCIO} = 5.0 V	C _L = 35 pF		0.3		0.4		0.3	ns
t _{OD2}	Output buffer and pad delay Slow slew rate = off, V _{CCIO} = 3.3 V	C _L = 35 pF		0.8		0.9		0.8	ns
t _{OD3}	Output buffer and pad delay Slow slew rate = on, V _{CCIO} = 5.0 V or 3.3 V	C _L = 35 pF		5.3		5.4		5.3	ns
t _{ZX1}	Output buffer enable delay Slow slew rate = off, V _{CCIO} = 5.0 V	C _L = 35 pF		4.0		4.0		4.0	ns
t _{ZX2}	Output buffer enable delay Slow slew rate = off, V _{CCIO} = 3.3 V	C _L = 35 pF		4.5		4.5		4.5	ns
t _{ZX3}	Output buffer enable delay Slow slew rate = on, V _{CCIO} = 5.0 V or 3.3 V	C _L = 35 pF		9.0		9.0		9.0	ns
t _Z	Output buffer disable delay	C _L = 5 pF ^[3]		4.0		4.0		4.0	ns
t _{SU}	Register setup time		1.4		0.8		1.0		ns
t _H	Register hold time		0.8		1.0		1.7		ns
t _{RD}	Register delay			1.2		1.4		1.6	ns
t _{COMB}	Combinatorial delay			1.3		1.0		1.6	ns
t _{IC}	Array clock delay			1.9		2.3		2.7	ns
t _{EN}	Register enable time			1.8		2.3		2.5	ns
t _{GLOB}	Global control delay			1.0		0.9		1.1	ns
t _{PRE}	Register preset time			2.3		2.6		2.3	ns
t _{CLR}	Register clear time			2.3		2.6		2.3	ns
t _{LIA}	LIA delay			0.7		0.8		1.3	ns

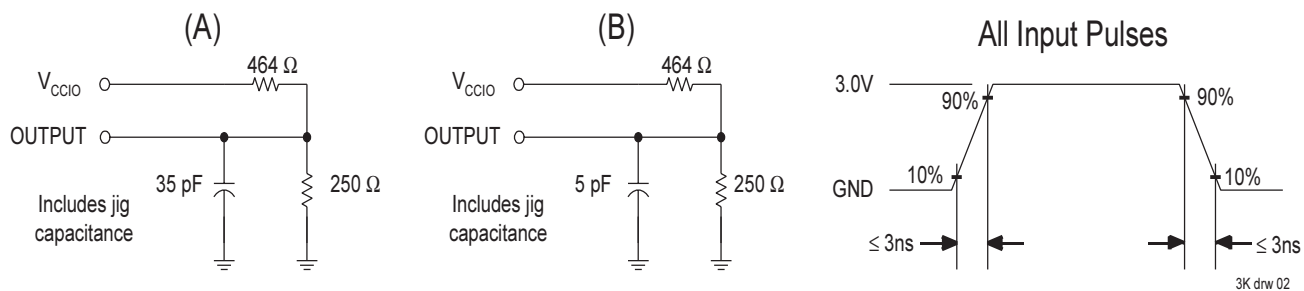
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AC Electrical Specifications cont.

Symbol	Parameter	Conditions	Speed: -7		Speed: -10		Unit
			Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.4		0.6	ns
t_{IO}	I/O input pad and buffer delay			0.4		0.6	ns
t_{SEXP}	Shared expander delay			3.6		4.9	ns
t_{PEXP}	Parallel expander delay			0.8		1.1	ns
t_{LAD}	Logic array delay			3.7		5.0	ns
t_{LAC}	Logic control array delay			3.4		4.6	ns
t_{IOE}	Internal output enable delay			0.0		0.0	ns
t_{OD1}	Output buffer and pad delay Slow slew rate = off, $V_{CCIO} = 5.0\text{ V}$	$C_L = 35\text{ pF}$		0.6		0.7	ns
t_{OD2}	Output buffer and pad delay Slow slew rate = off, $V_{CCIO} = 3.3\text{ V}$	$C_L = 35\text{ pF}$		1.1		1.2	ns
t_{OD3}	Output buffer and pad delay Slow slew rate = on, $V_{CCIO} = 5.0\text{ V}$ or 3.3 V	$C_L = 35\text{ pF}$		5.6		5.7	ns
t_{ZX1}	Output buffer enable delay Slow slew rate = off, $V_{CCIO} = 5.0\text{ V}$	$C_L = 35\text{ pF}$		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay Slow slew rate = off, $V_{CCIO} = 3.3\text{ V}$	$C_L = 35\text{ pF}$		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay Slow slew rate = on, $V_{CCIO} = 5.0\text{ V}$ or 3.3 V	$C_L = 35\text{ pF}$		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C_L = 5\text{ pF}^{[3]}$		4.0		5.0	ns
t_{SU}	Register setup time		1.3		1.7		ns
t_H	Register hold time		2.4		3.8		ns
t_{RD}	Register delay			2.1		2.8	ns
t_{COMB}	Combinatorial delay			1.5		2.0	ns
t_{IC}	Array clock delay			3.4		4.6	ns
t_{EN}	Register enable time			3.4		4.6	ns
t_{GLOB}	Global control delay			1.4		1.8	ns
t_{PRE}	Register preset time			3.9		5.2	ns
t_{CLR}	Register clear time			3.9		5.2	ns
t_{LIA}	LIA delay			1.3		1.7	ns

3KA tbl 07A2

AC Test Conditions



Notes to Tables

1. During transitions, inputs may undershoot to -2.0V for periods shorter than 20ns. Otherwise, minimum DC input voltage is 0.3V.
2. Typical values are at V_{CC} of 5.0 volts and ambient temperature of 25 °C.
3. Guaranteed but not tested. Characterized initially, and after any design changes which may affect these parameters.
4. Internal timing delays are based on characterization, and cannot be explicitly tested. Internal timing parameters should be used for performance estimation only.

Revision History

- | | |
|---------------|-------------------------------------|
| 20 Oct. 2000: | Created preliminary document. |
| 1 Dec. 2000: | Updated application note reference. |

Ordering Information

Part Number	Temperature Range	Package Type	Speed	Altera Equivalent
CL3256ATC144-10	Commercial	144-pin Thin QFP	-10	EPM3256ATC144-10
CL3256ATC144-7			-7	EPM3256ATC144-7
CL3256ATC144-6			-6	EPM3256ATC144-6
CL3256ATC144-5			-5	N/A
CL3256AQC208-10	Commercial	208-pin Plastic QFP	-10	EPM3256AQC208-10
CL3256AQC208-7			-7	EPM3256AQC208-7
CL3256AQC208-6			-6	EPM3256AQC208-6
CL3256AQC208-5			-5	N/A

3256A tbl 02